Notice	of References	Cited
--------	---------------	-------

Application/Control No.	Applicant(s)/Pater	nt Under
10/551,720	Reexamination JEON ET AL.	
Examiner	Art Unit	
SHINLHON CHEN	2131	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0124966	07-2004	Forrest, Simon J.	340/005.8
*	В	US-2003/0120925	06-2003	Rose et al.	713/176
*	С	US-7,130,454	10-2006	Berube et al.	382/118
*	D	US-2003/0236991	12-2003	Letsinger, Reed	713/200
	Е	US-			
	F	US-			
	G	US-		-	
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	٦	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	ø					
	R					
	s					
	Т					

## NON DATENT DOCUMENTS

	NON-PATENT DOCUMENTS				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	v				
	w				
	x				

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.